

Measurement report TRAC-CAL

Machine info:

Machine:	Example Machine
Serial No.:	
Machine volume [X,Y,Z] [mm]:	[800,600,500]
Expansion coefficient of scales:	11.7 $\mu\text{m}/(\text{m}^{\circ}\text{K})$
Date of examination:	
Examiner:	ETALON
Company:	Company
Department:	
Comments:	

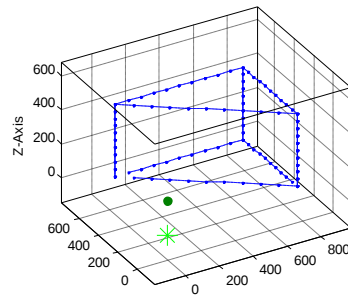
Uncertainty model TRACER/TRACKER:

Static uncertainty:	0.2 μm (k=2)
Length dependent (random):	0.2 $\mu\text{m}/\text{m}$ (k=2)
Length dependent (systematic):	0.2 $\mu\text{m}/\text{m}$ (k=2)
Reflector offset Uncertainty:	2 mm

Software Info:

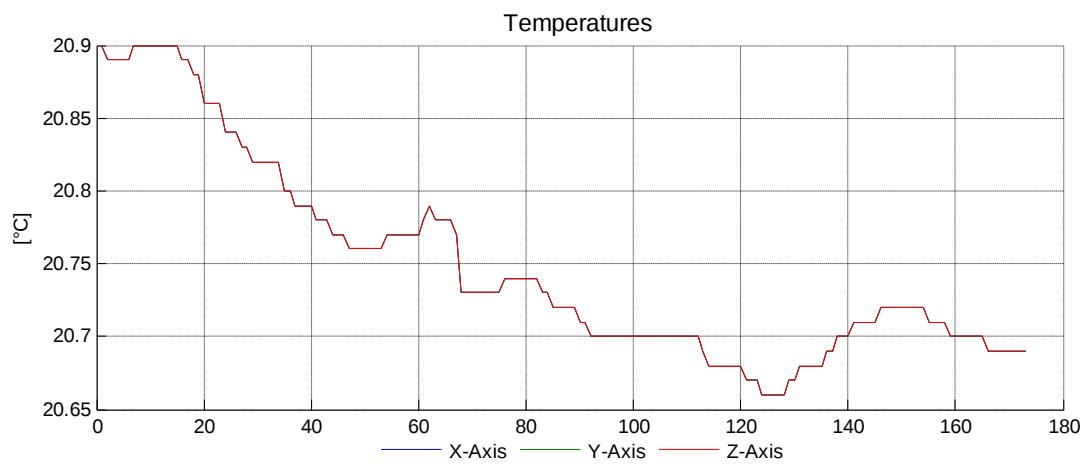
Software:	Trac-Cal
Version (measurement):	V20.99.2009-09-11
Version (report):	V20.113.2009-09-30

1. Measurement , Position 1

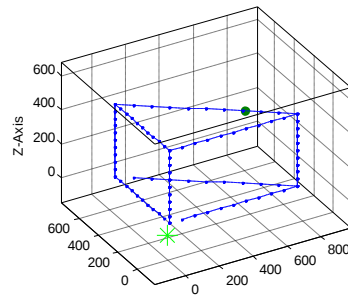


Y-Axis

	X [mm]	Y [mm]	Z [mm]
Measured Tracker position	51.78	108.59	159.51
reflector offset	0.0	0.0	0.0

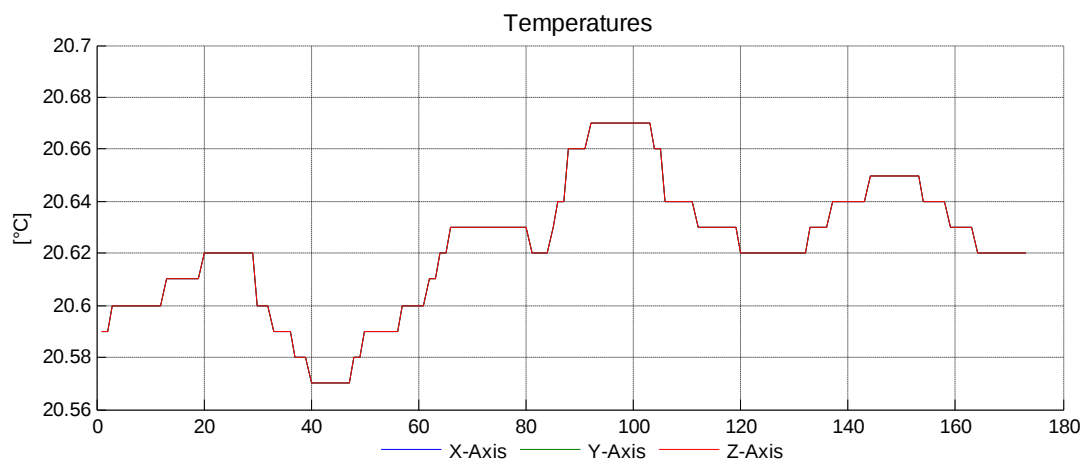


2. Measurement , Position 3

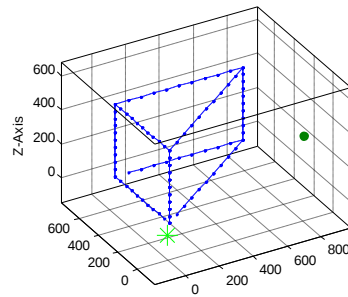


Y-Axis

	X [mm]	Y [mm]	Z [mm]
Measured Tracker position	805.49	471.75	159.49
reflector offset	0.0	0.0	0.0

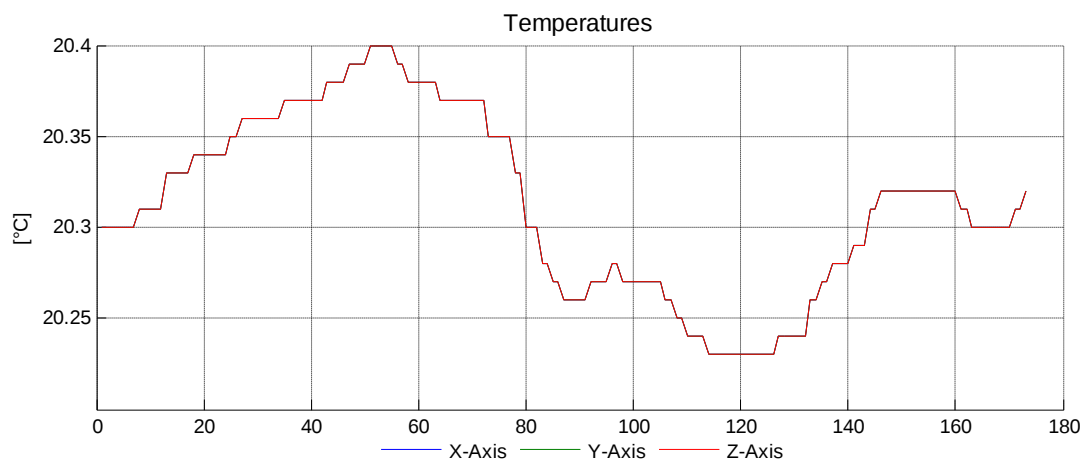


3. Measurement , Position 4

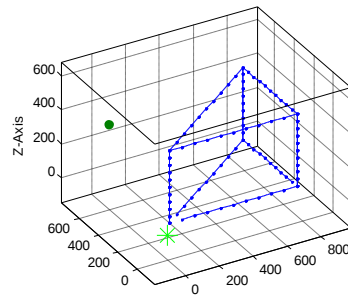


Y-Axis

	X [mm]	Y [mm]	Z [mm]
Measured Tracker position	811.85	153.30	289.14
reflector offset	0.0	0.0	0.0

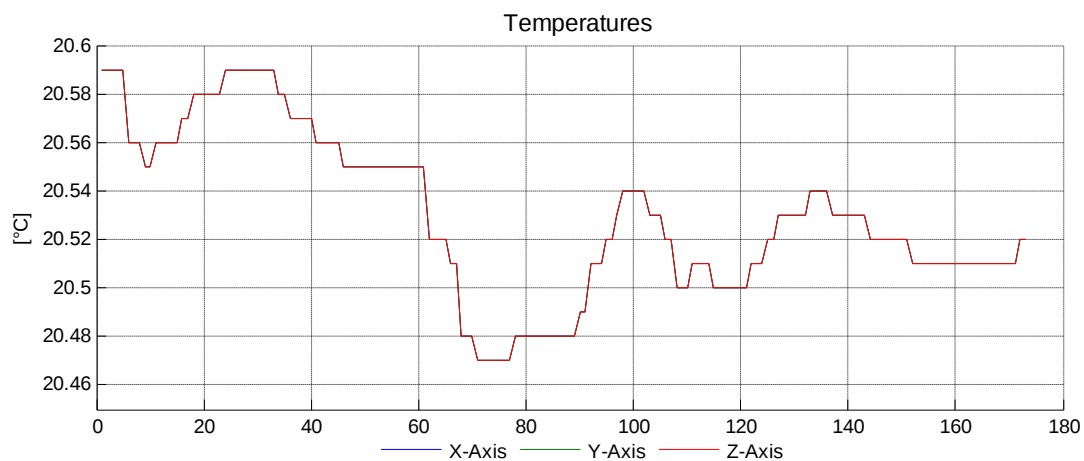


4. Measurement , Position 2



Y-Axis

	X [mm]	Y [mm]	Z [mm]
Measured Tracker position	98.33	405.78	289.12
reflector offset	0.0	0.0	0.0



Uncertainties

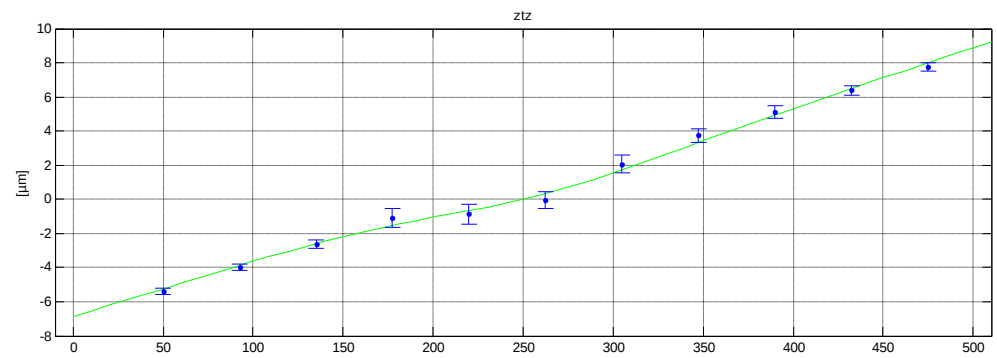
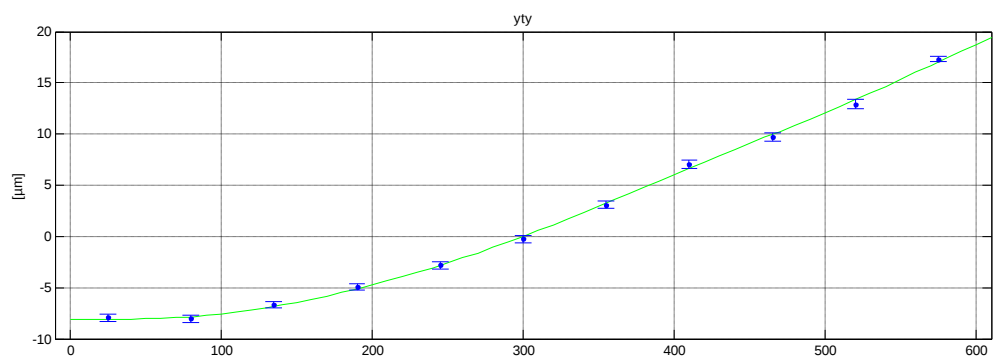
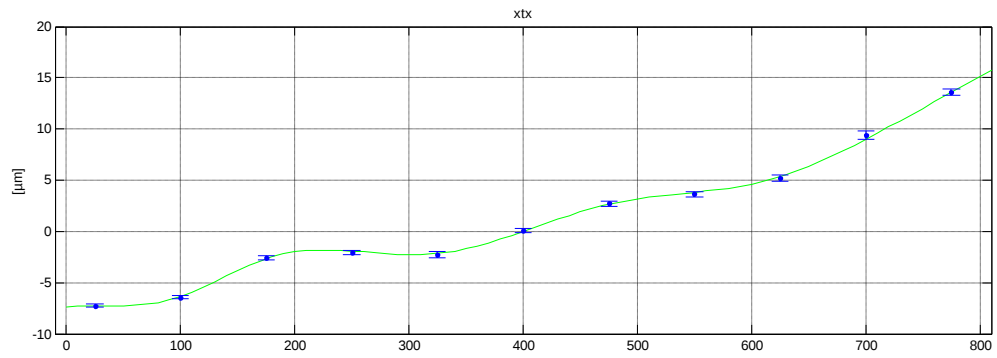
Deviation parameters (k=2):

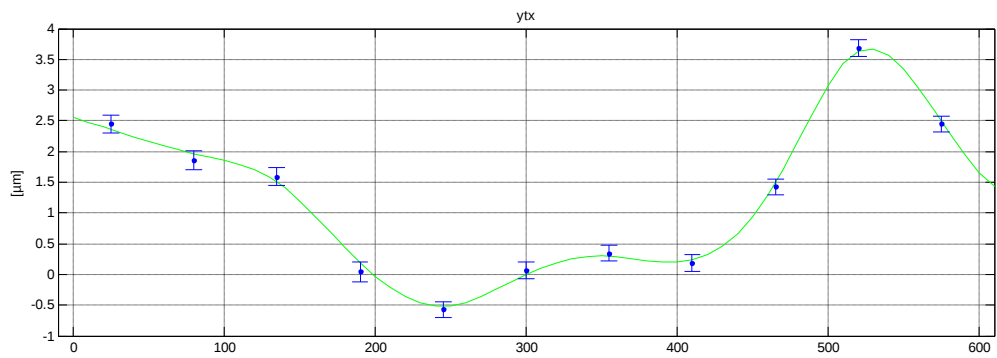
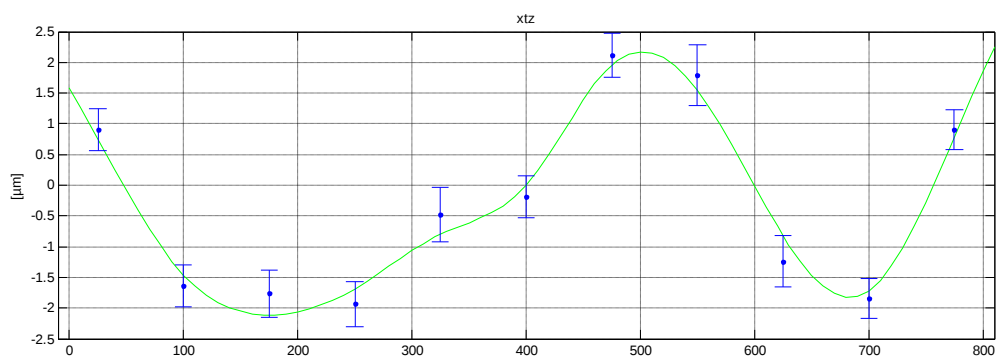
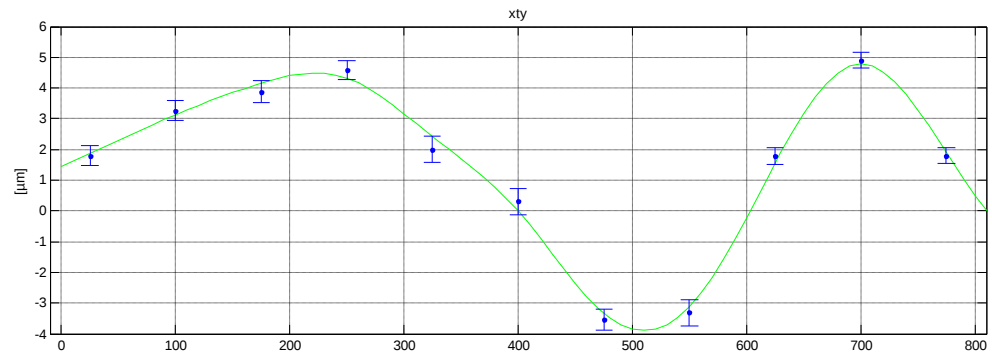
Name	U (max)	Unit
xtx	0.4	μm
xy	0.4	μm
xtz	0.5	μm
ytx	0.2	μm
yty	0.5	μm
ytz	0.4	μm
ztx	0.1	μm
zty	0.2	μm
ztz	0.6	μm
xrx	1.3	μrad
xry	0.7	μrad
xrz	1.2	μrad
yrx	1.4	μrad
yry	0.5	μrad
xwy	0.7	μrad
xwz	0.4	μrad
ywz	0.6	μrad
krx	0.0	μrad
kry	0.0	μrad
krz	0.0	μrad

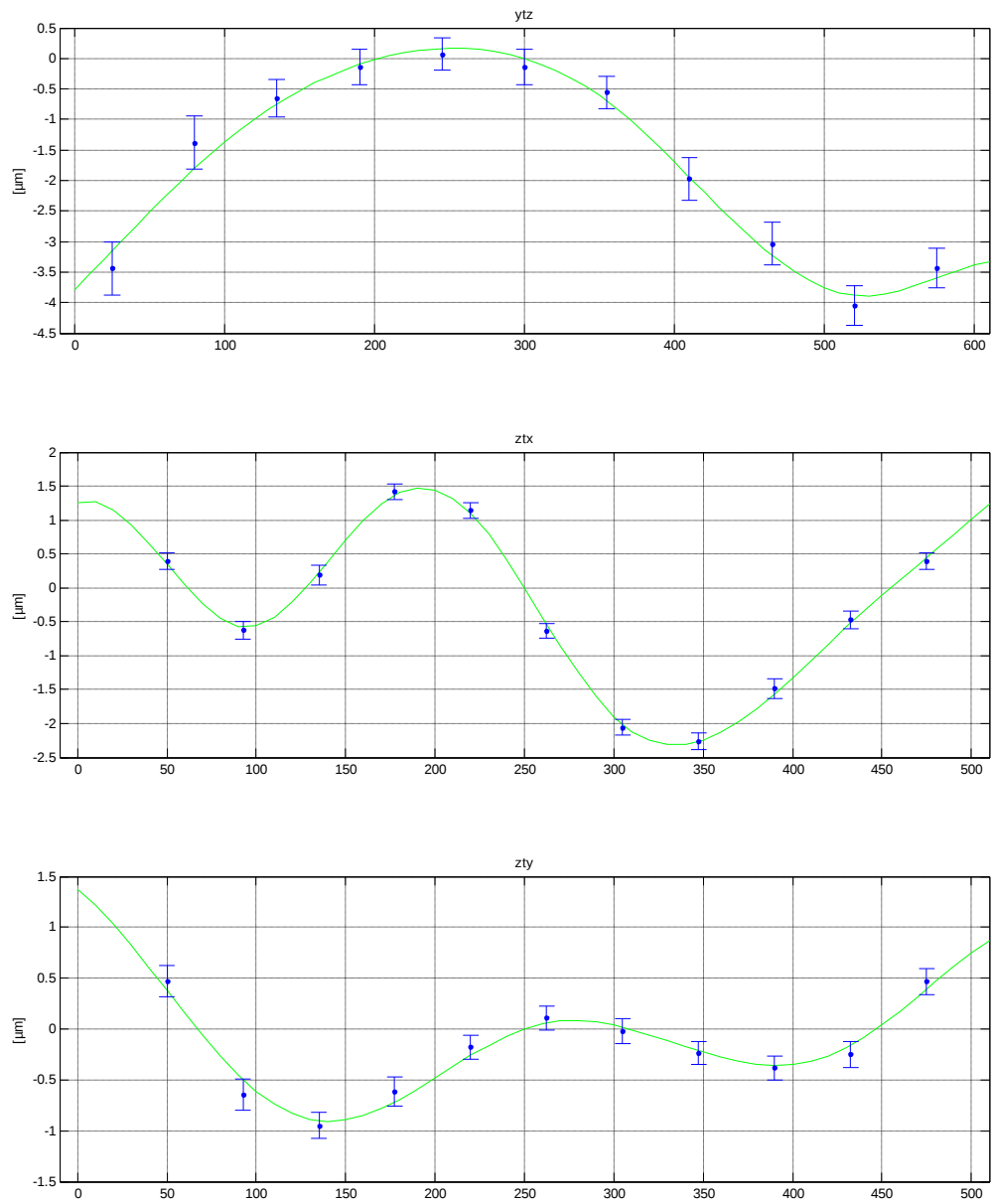
Measuring results (guidance deviation):

Squareness deviations:

	μrad	"
xwy	10.3	2.1
xwz	-19.1	-3.9
ywz	-2.5	-0.5

Position deviations:

Straightness deviations:



Pitch / Yaw / Roll: